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| FIRST NAMED INVENTOR | ATTORNEY DOCKET NO. | CONFIRMATION NO. |
|--------------------------------|---------------------|---|
| Donald J. Cook | BUR920000172US | 8838 |
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| | EXAMINER | |
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| | ART UNIT | PAPER NUMBER |
| | 2829 | |
| DATE MAILED: 07/29/2002 | | |
| | Donald J. Cook | Donald J. Cook BUR920000172US EXAM KOBERT, RUS ART UNIT 2829 |

Please find below and/or attached an Office communication concerning this application or proceeding.

| | A | | | KE |
|--|---|---|--|----------|
| | | Application No. | Applicant(s) | |
| | | 09/751,355 | COOK ET AL. | |
| Offic Action Summary | nary | Examiner | Art Unit | |
| | | Russell M Kobert | 2829 | |
| The MAILING DATE of this Period for Reply | communication appe | ars on the cov r sheet w | ith th correspond nce address | |
| A SHORTENED STATUTORY PE THE MAILING DATE OF THIS CO - Extensions of time may be available under the after SIX (6) MONTHS from the mailing date of - If the period for reply specified above is less to - If NO period for reply is specified above, the - Failure to reply within the set or extended per - Any reply received by the Office later than three earned patent term adjustment. See 37 CFR Status | DMMUNICATION. Be provisions of 37 CFR 1.136 of this communication. han thirty (30) days, a reply w naximum statutory period will iod for reply will, by statute, c be months after the mailing de | (a). In no event, however, may a within the statutory minimum of this apply and will expire SIX (6) MON ause the application to become Al | eply be timely filed by (30) days will be considered timely. ITHS from the mailing date of this communi BANDONED (35 U.S.C. § 133). | cation. |
| 1) Responsive to communication | tion(s) filed on <u>28 De</u> | ecember 2000 . | | |
| 2a)☐ This action is FINAL . | 2b)⊠ This | action is non-final. | | |
| 3) Since this application is in closed in accordance with Disposition of Claims | | | tters, prosecution as to the me D. 11, 453 O.G. 213. | rits is |
| 4)⊠ Claim(s) <u>1-17</u> is/are pendin | g in the application. | | | |
| 4a) Of the above claim(s) | is/are withdrawr | n from consideration. | | |
| 5) Claim(s) is/are allowed | ed. | | | |
| 6)⊠ Claim(s) <u>1-17</u> is/are rejected | 1 . | | | |
| 7) Claim(s) is/are objec | ted to. | | | |
| 8) Claim(s) are subject | to restriction and/or | election requirement. | | |
| Application Papers | | | | |
| 9) The specification is objected | to by the Examiner. | | | |
| 10) The drawing(s) filed on | _ is/are: a)□ accepte | ed or b) objected to by t | he Examiner. | |
| Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a). | | | | |
| 11) The proposed drawing correct | | | lisapproved by the Examiner. | |
| If approved, corrected drawin | | | | |
| 12) The oath or declaration is ob | - | miner. | | |
| Priority under 35 U.S.C. §§ 119 and | | | | |
| 13) Acknowledgment is made o | | oriority under 35 U.S.C. | § 119(a)-(d) or (f). | |
| a) ☐ All b) ☐ Some * c) ☐ N | | | | |
| 1. Certified copies of the | | | | |
| • | • | have been received in A | | |
| | he International Bure | au (PCT Rule 17.2(a)). | received in this National Stage received. |) |
| 14) Acknowledgment is made of | a claim for domestic | priority under 35 U.S.C. | § 119(e) (to a provisional appli | cation). |
| a) ☐ The translation of the fo 15)☐ Acknowledgment is made of | | | | |
| Attachment(s) | | | | |
| 1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing 3) Information Disclosure Statement(s) (PT | | | Summary (PTO-413) Paper No(s) Informal Patent Application (PTO-152) | <u> </u> |

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1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that

form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(e) the invention was described in-

(1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effect under this subsection of a national application published under section 122(b) only if the international application designating the United States was

published under Article 21(2)(a) of such treaty in the English language; or

(2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that a patent shall not be deemed filed in the United States for the purposes of this subsection based on the filing of an international application filed under

the treaty defined in section 351(a).

2. Claims 1, 3-6, 8, 15-17 are rejected under 35 U.S.C. 102(e) as being anticipated

by Hembree et al (6181144).

Hembree et al anticipates a system (Figures 6A and 6B) for testing a DUT (12)

having a plurality of probe pads (14Vcc-1, 14Vcc-2, etc.), comprising:

A forcing probe for contacting and applying a first electrical signal to a first one of

the plurality of probe pads;

A sensing probe (either one of 22-1 or 22-2) for contacting the first one of the

plurality of probe pads and sensing a second electrical signal at the first one of the

plurality of probe pads; and

A variable power supply (inherent to the multimeter 38) in electrical

communication with the forcing probe and the sensing probe, the variable power supply

capable of adjusting the first electrical signal based upon the second electrical signal

(col 8, In 51-63); as recited in claim 1.

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Hembree et al anticipates a method of testing a DUT having a plurality of probe pads, comprising the steps of:

Providing a first electrical signal to one of the plurality of probe pads;

Sensing a second electrical signal at the one of the plurality of probe pads; and

Adjusting the first electrical signal based upon the second electrical signal (col 8, ln 16-27, 51-63); as recited in claim 9.

As to claim 3, having a voltmeter electrically connected between the sensing probe and the variable power supply, the voltmeter for measuring the second electrical signal is anticipated (col 7, ln 54-58);

As to claim 4, a probe card (20) supporting the forcing probe and the sensing probe is shown;

As to claim 5, first and second sensing electrodes (36-1B and 36-2B) and a sensing instrument (38), the first sensing electrode in electrical communication with the variable power supply, the second sensing electrode in electrical communication with the sensing instrument is shown;

As to claim 6, the sensing instrument being a current meter is anticipated (a current meter is a function of multimeter 36)

As to claim 8, a feedback controller electrically connected between the sensing probe and the variable power supply is anticipated (col 8, ln 51-63);

As to claim 15, having the first electrical signal provided via a forcing probe (either one of 22-1 or 22-2) and a power supply (inherent to the multimeter 38) in electrical communication with the forcing probe is shown;

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As to claim 16, the power supply having a feedback controller for adjusting the

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first electrical signal based upon the second electrical signal is anticipated (col 8, In 51-

63);

As to claim 17, the step of providing a feedback signal in proportion to the

second electrical signal for adjusting the first electrical signal is anticipated (col 8, In 51-

63).

3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all

obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the

the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains.

Patentability shall not be negatived by the manner in which the invention was made.

This application currently names joint inventors. In considering patentability of

the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of

the various claims was commonly owned at the time any inventions covered therein

were made absent any evidence to the contrary. Applicant is advised of the obligation

under 37 CFR 1.56 to point out the inventor and invention dates of each claim that was

not commonly owned at the time a later invention was made in order for the examiner to

consider the applicability of 35 U.S.C. 103(c) and potential 35 U.S.C. 102(e), (f) or (g)

prior art under 35 U.S.C. 103(a).

4. Claims 2, 10, 11, 12 and 14 are rejected under 35 U.S.C. 103(a) as being

unpatentable over Hembree et al (6181144).

It would have been obvious to one having ordinary skill in the art at the time the invention was made to have used a plurality of forcing probes and a plurality of variable power supplies, each of the forcing probes being in electrical communication with a corresponding one of the plurality of power supplies as mentioned in claim 2, a plurality of first electrical signals and a plurality of second electrical signals as further described in claim 11 and a plurality of forcing probes along with a plurality of power supplies as further described in claim 12 because it has been held that mere duplication of the essential working parts of a device involves only routine skill in the art (193 USPQ 8).

As to claim 10, measuring a third electrical signal at a second one of the plurality of probe pads only requires routine skill in the art because the process duplicates the sensing step of claim 9 for a duplicate probe pad;

As to claim 14, having each of the power supplies including a feedback controller for adjusting a corresponding one of the plurality of first electrical signals based upon a corresponding one of the plurality of second electrical signals is shown in Hembree et al (Figure 7 and col 8, In 51-63).

5. Claims 7 and 13 are rejected under 35 U.S.C. 103(a) as being unpatentable over Hembree et al (6181144) in view of Bove et al (4038599).

Bove et al shows a plurality of forcing probes (19), a plurality of variable power supplies (T1-T9) and a switching matrix (Figure 4), the plurality of forcing probes being selectively connectable to the plurality of variable power supplies via the switching matrix (col 9, In 12 – col 10, In 47) as mentioned in claims 7 and 13.

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It would have been obvious to one having ordinary skill in the art at the time the

invention was made to have combined the teaching of Bove et al with that of Hembree

et al to make the claimed invention because each teach the determination of the

electrical integrity of a conductive path between two pads on a device under test (col 10.

In 45-47).

6. The prior art made of record and not relied upon is considered pertinent to

applicant's disclosure.

LeCroy, Jr. (4423373) shows a dual test probe.

7. A shortened statutory period for response to this action is set to expire three

month(s) from the date of this letter. Failure to respond within the period for response

will cause the application to become abandoned. 35 U.S.C. 133

Any inquiry concerning this communication or earlier communications from the

examiner should be directed to Russell Kobert whose telephone number is (703) 308-

5222.

Any inquiry of a general nature or relating to the status of this application should

be directed to the Group receptionist whose telephone number is (703) 308-0956.

Russell M. Kobert

Patent Examiner Group Art Unit 2829

July 23, 2002

MICHAEL SHERRY SUPERVISORY PATENT EXAMINER

TECHNOLOGY CENTER 2800

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